www.ti.com.cn

高频 4A 灌电流同步场效应晶体管 (MOSFET) 驱动器

查询样品: TPS28225-Q1, TPS28226-Q1

特性

- 符合汽车应用要求
- 符合 AEC-Q100 标准的下列结果:
 - 器件温度 2 级: -40°C 至 105°C 的环境运行温度范围
 - 器件人体模型 (HBM) 静电放电 (ESD) 分类等级 H2
 - 器件充电器件模型 (CDM) ESD 分类等级 C3B
- 驱动 2 个自适应死区时间为 14ns 的 N-通道 MOSFET
- 宽栅极驱动电压范围: 4.5V 到最高 8.8V, 7V 到 8V 间效率最佳
- 宽电源系统输入电压: 3V 到最高 27V
- 宽输入脉宽调制 (PWM) 信号: 2.0V 到最高 13.2V 振幅
- 能驱动每相位电流值 ≥ 40A 的 MOSFET
- 高频运行: 14ns 广播延迟和 10ns 上升/下降时间 允许 F_{sw}-2MHz
- 支持传播延迟 < 30ns 的输入 PWM 脉冲
- 低侧驱动器导通电阻 (0.4Ω) 防止与电压上升率 (dV/dT) 相关的击穿电流
- 用于电源级关断的 3 态 PWM 输入
- 为了节省空间,实现使能(输入)和电源正常(输出)信号在同一引脚上
- 热关断
- 欠压闭锁 (UVLO) 保护
- 内部自举二极管
- 经济型小外型尺寸集成电路 (SOIC) 8 引脚和耐热 增强型 3mm x 3mm 双边扁平无引线(DFN) 8 引脚 封装
- 针对普遍使用的 3 态输入驱动器的高性能替代产品

应用范围

- 具有模拟或者数字控制的多相位直流 DC 到 DC 转 换器
- 桌面和服务器电压调节模块 (VRM) 和虚拟远程桌面 (EVRD)
- 便携式/笔记本稳压器
- 隔离式电源的同步整流

说明

TPS28225-Q1 和 TPS28226-Q1 是高速驱动器,此驱动器用于驱动具有自适应死区时间控制的 N-通道互补驱动功率 MOSFET。 这些驱动器针对多种高电流单一相位和多相位 dc 到 dc 转换器中的应用进行了优化。TPS28225-Q1 是一个提供高效、小尺寸、低电磁干扰(EMI) 发射的解决方案。

通过 8.8V 栅极驱动电压,14ns 自适应死区时间控制,14ns 广播延迟和 2A 高源电流和 4A 灌电流驱动能力,可实现这一性能。 较低栅极驱动器的 0.4Ω 阻抗保持功率 MOSFET 的栅极低于它的阀值并确保在dV/dt 相位结点转换中不会产生击穿电压。 由内部二极管充电的自举电容器允许在半桥配置中使用 N-通道MOSFET。

TPS28225-Q1 特有一个 3 态 PWM 输入,此输入与采用 3 态输出特性的多相位控制器兼容。 只要此输入停留在 3 态窗口的持闭时间达到 250ns,此驱动器将两个输出都切换至低位。 此关断模式避免了来自反向输出电压的负载。

其它的特性包括欠压闭锁, 热关断和双向使能/电源正常信号。 没有 3 态特性控制器的系统可以使用使能/电源正常输入/输出来在关断期间将两个输出保持在低位。

TPS28225-Q1 采用经济型小外型尺寸集成电路 (SOIC) 8 引脚和耐热增强型小尺寸双边扁平无引线 (DFN-8) 封装方式。 此驱动器额定扩展温度范围为 -40°C 至 105°C,绝对最大结温为 105°C。 除了输入 欠压闭锁,TPS28226-Q1 的工作方式与 TPS28225-Q1 一样。 除非另外注明,否则所有对于 TPS28225-Q1 的参考也适用于 TPS28226-Q1。



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FUNCTIONAL BLOCK DIAGRAM

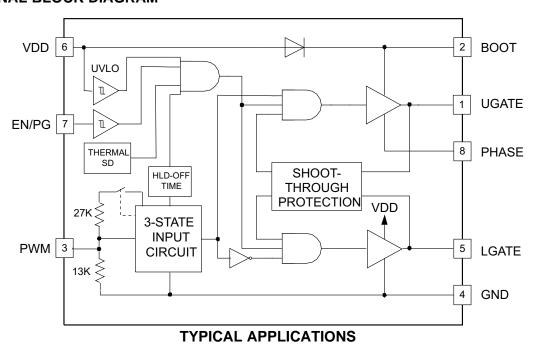
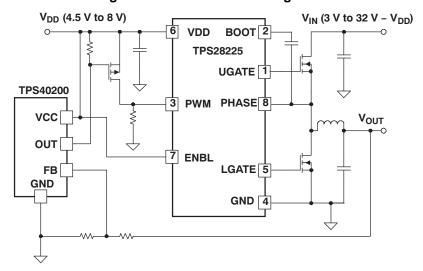


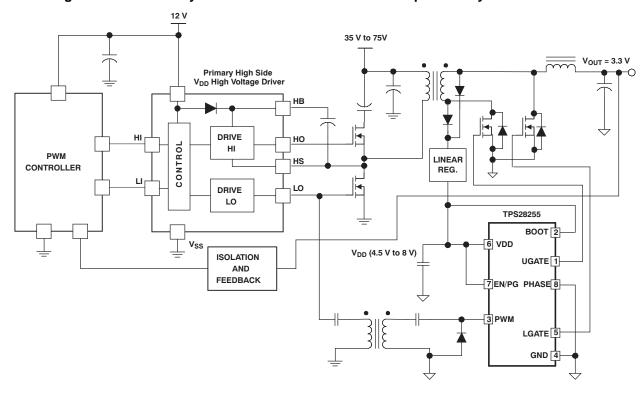
Figure 1. One-Phase POL Regulator





TYPICAL APPLICATIONS (continued)

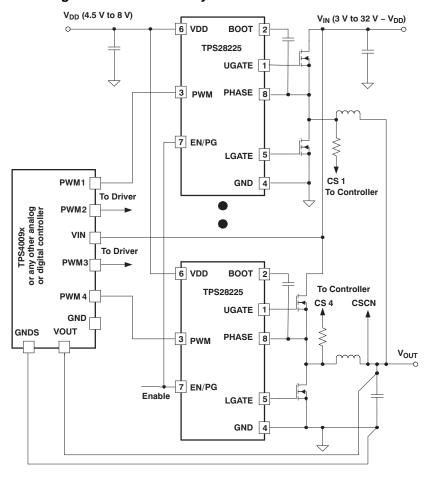
Figure 2. Driver for Synchronous Rectification with Complementary Driven MOSFETs





TYPICAL APPLICATIONS (continued)

Figure 3. Multi-Phase Synchronous Buck Converter



ORDERING INFORMATION (1) (2)

T _A	PACI	KAGE	ORDERABLE PART NUMBER	TOP-SIDE MARKING
	SOIC (D)	Dool of 2500	TPS28225TDRQ1	PREVIEW
40°C to 405°C		Reel of 2500	TPS28226TDRQ1	PREVIEW
-40°C to 105°C	DEN (DDD)	Dool of 2000	TPS28225TDRBRQ1	PXND
	DFN (DRB)	Reel of 3000	TPS28226TDRBRQ1	PREVIEW

⁽¹⁾ The SOIC-8 (D) and DFN-8 (DRB) package uses in Pb-Free lead finish of Pd-Ni-Au which is compatible with MSL level 1 at 255°C to 260°C peak reflow temperature to be compatible with either lead free or Sn/Pb soldering operations.

⁽²⁾ In the DFN package, the pad underneath the center of the device is a thermal substrate. The PCB "thermal land" design for this exposed die pad should include thermal vias that drop down and connect to one or more buried copper plane(s). This combination of vias for vertical heat escape and buried planes for heat spreading allows the DFN to achieve its full thermal potential. This pad should be either grounded for best noise immunity, and it should not be connected to other nodes.



ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted) (1) (2)

		VALUE	UNIT	
Input supply voltage range	e, V _{DD} ⁽³⁾	-0.3 to 8.8	V	
Boot voltage, V _{BOOT}		-0.3 to 33	V	
Dhana waltana M	DC	−2 to 32 or V _{BOOT} + 0.3 − V _{DD} whichever is less	\/	
Phase voltage, V _{PHASE}	Pulse < 400 ns, E = 20 μJ	-7 to 33.1 or V _{BOOT} + 0.3 – V _{DD} whichever is less	V	
Input voltage range, V _{PWM}	, V _{EN/PG}	-0.3 to 13.2	V	
Output voltage range,		$V_{PHASE} - 0.3$ to $V_{BOOT} + 0.3$, $(V_{BOOT} - V_{PHASE} < 8.8)$	V	
V_{UGATE}	Pulse < 100 ns, E = 2 μJ	$V_{PHASE} - 2$ to $V_{BOOT} + 0.3$, $(V_{BOOT} - V_{PHASE} < 8.8)$		
Output voltage range,		-0.3 to V _{DD} + 0.3	V	
V_{LGATE}	Pulse < 100 ns, E = 2 μJ	−2 to V _{DD} + 0.3	V	
ECD actions	(HBM) AEC-Q100 Classification Level H2	2	kV	
ESD rating	(CDM) AEC-Q100 Classification Level C3B	750	V	
Operating virtual junction temperature range, T _J		-40 to 150	°C	
Operating ambient temperature range, T _A		-40 to 105	°C	
Storage temperature, T _{stq}		-65 to 150	°C	
Lead temperature (solderi	ng, 10 sec.)	300		

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

THERMAL INFORMATION

	THERMAL METRIC ⁽¹⁾	TPS28225TDRBRQ1	LINUTO
	THERMAL METRIC**	DRB (8 PINS)	UNITS
θ_{JA}	Junction-to-ambient thermal resistance	50.2	
θ_{JCtop}	Junction-to-case (top) thermal resistance	57.5	
θ_{JB}	Junction-to-board thermal resistance	25.9	000
Ψ_{JT}	Junction-to-top characterization parameter	1.5	°C/W
ΨЈВ	Junction-to-board characterization parameter	26.0	
θ_{JCbot}	Junction-to-case (bottom) thermal resistance	9.5	

(1) 有关传统和全新热度量的更多信息,请参阅 IC 封装热度量 应用报告 (文献号:SPRA953)。

RECOMMENDED OPERATING CONDITIONS

over operating free-air temperature range (unless otherwise noted)

		MIN	TYP	MAX	UNIT
	Input supply voltage (TPS28225-Q1)	4.5	7.2	8	
V_{DD}	Input supply voltage (TPS28226-Q1)	6.8	7.2	8	V
V _{IN}	Power input voltage for the TPS28225-Q1	3		$32 V_{-VDD}$	
T_{J}	Operating junction temperature range	-40		125	°C

²⁾ These devices are sensitive to electrostatic discharge; follow proper device handling procedures.

⁽³⁾ All voltages are with respect to GND unless otherwise noted. Currents are positive into, negative out of the specified terminal. Consult Packaging Section of the Data book for thermal limitations and considerations of packages.



ELECTRICAL CHARACTERISTICS(1)

 V_{DD} = 7.2 V, EN/PG pulled up to V_{DD} by 100-k Ω resistor, T_A = -40°C to 105°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
UNDEF	R VOLTAGE LOCKOUT	,			,	
	Rising threshold (TPS28225-Q1)		3.2	3.5	3.8	
	Rising threshold (TPS28226-Q1)			6.35	6.70	
	Falling threshold (TPS28225-Q1)	$V_{PWM} = 0 V$	2.7	3.0		V
	Falling threshold (TPS28226-Q1)		4.7	5.0		
	Hysteresis (TPS28225-Q1)			0.5		
	Hysteresis (TPS28226-Q1)		1.00	1.35		
BIAS C	CURRENTS	1	"			
I _{DD(off)}	Bias supply current	V _{EN/PG} = low, PWM pin floating		350		
I _{DD}	Bias supply current	V _{EN/PG} = high, PWM pin floating		500		μΑ
INPUT	(PWM)	,			,	
	land comed	V _{PWM} = 5 V		185		
I _{PWM}	Input current	V _{PWM} = 0 V		-200		μΑ
	PWM 3-state rising threshold ⁽²⁾			1.0		.,
	PWM 3-state falling threshold	V _{PWM} PEAK = 5 V	3.4	3.8	4.0	V
t _{HLD_R}	3-state shutdown Hold-off time			250		
T _{MIN}	PWM minimum pulse to force U _{GATE} pulse	$C_L = 3 \text{ nF at } U_{GATE}$, $V_{PWM} = 5 \text{ V}$		30		ns
ENABL	LE/POWER GOOD (EN/PG)	,			,	
	Enable high rising threshold	PG FET OFF		1.7	2.1	
	Enable low falling threshold	PG FET OFF	0.8	1.0		
	Hysteresis		0.35	0.70		V
	Power good output	V _{DD} = 2.5 V			0.2	
UPPER	R GATE DRIVER OUTPUT (UGATE)	,			,	
	Source resistance	500 mA source current		1.0	2.0	Ω
	Source current (2)	V _{UGATE-PHASE} = 2.5 V		2.0		Α
t _{RU}	Rise time	C _L = 3 nF		10		ns
	Sink resistance	500 mA sink current		1.0	2.0	Ω
	Sink current (2)	V _{UGATE-PHASE} = 2.5 V		2.0		Α
t _{FU}	Fall time	C _L = 3 nF		10		ns

⁽¹⁾ Typical values for T_A = 25°C(2) Not tested in production



ELECTRICAL CHARACTERISTICS(1) (continued)

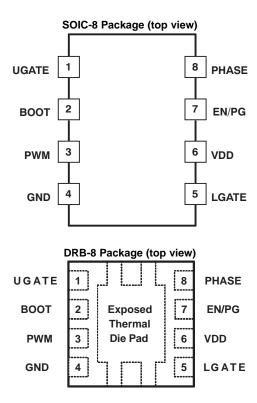
 V_{DD} = 7.2 V, EN/PG pulled up to V_{DD} by 100-k Ω resistor, T_A = -40°C to 105°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
LOWE	R GATE DRIVER OUTPUT (LGATE)					
	Source resistance	500 mA source current		1.0	2.0	Ω
	Source current ⁽³⁾	V _{LGATE} = 2.5 V		2.0		Α
t_{RL}	Rise time ⁽³⁾	C _L = 3 nF		10		ns
	Sink resistance	500 mA sink current		0.4	1.0	Ω
	Sink current ⁽³⁾	$V_{LGATE} = 2.5 V$		4.0		Α
	Fall time ⁽³⁾	$C_L = 3 \text{ nF}$		5		ns
SWIT	CHING TIME					
t_{DLU}	UGATE turn-off propagation Delay	C _L = 3 nF		14		
t _{DLL}	LGATE turn-off propagation Delay	C _L = 3 nF		14		
t _{DTU}	Dead time LGATE turn-off to UGATE turn-on	$C_L = 3 \text{ nF}$		14		ns
t_{DTL}	Dead time UGATE turn-off to LGATE turn-on	$C_L = 3 \text{ nF}$		14		
воот	STRAP DIODE					
V_{F}	Forward voltage	Forward bias current 100 mA		1.0		V
THER	MAL SHUTDOWN					
	Rising threshold ⁽³⁾		150	160	170	
	Falling threshold (3)		130	140	150	°C
	Hysteresis			20		

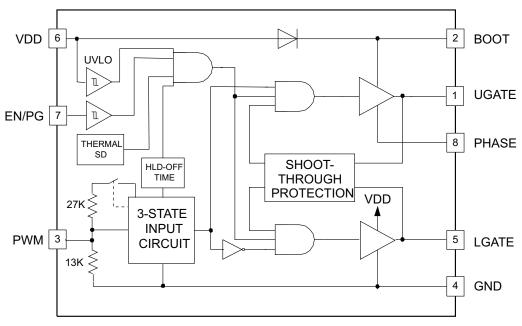
⁽³⁾ Not tested in production



DEVICE INFORMATION



BLOCK DIAGRAM



A. For the TPS28225-Q1DRB device the thermal PAD on the bottom side of package must be soldered and connected to the GND pin and to the GND plane of the PCB in the shortest possible way. See Recommended Land Pattern in the Application section.



TERMINAL FUNCTIONS

TERMINAL		1/0	DESCRIPTION				
SOIC-8	DRB-8	NAME	1/0	DESCRIPTION			
1	1	UGATE	0	Upper gate drive sink/source output. Connect to gate of high-side power N-Channel MOSFET.			
2	2	воот	I/O	Floating bootstrap supply pin for the upper gate drive. Connect the bootstrap capacitor between this pin and the PHASE pin. The bootstrap capacitor provides the charge to turn on the upper MOSFET.			
3	3	PWM	I	The PWM signal is the control input for the driver. The PWM signal can enter three distinct states during operation, see the 3-state PWM Input section under DETAILED DESCRIPTION for further details. Connect this pin to the PWM output of the controller.			
4	4	GND	_	Ground pin. All signals are referenced to this node.			
	Exposed die pad	Thermal pad	_	Connect directly to the GND for better thermal performance and EMI			
5	5	LGATE	0	Lower gate drive sink/source output. Connect to the gate of the low-side power N-Channel MOSFET.			
6	6	VDD	I	Connect this pin to a 5-V bias supply. Place a high quality bypass capacitor from this pin to GND.			
7	7	EN/PG	I/O	Enable/Power Good input/output pin with $1M\Omega$ impedance. Connect this pin to HIGH to enable and LOW to disable the device. When disabled, the device draws less than $350\mu A$ bias current. If the V_{DD} is below UVLO threshold or over temperature shutdown occurs, this pin is internally pulled low.			
8	8	PHASE	I	Connect this pin to the source of the upper MOSFET and the drain of the lower MOSFET. This pin provides a return path for the upper gate driver.			

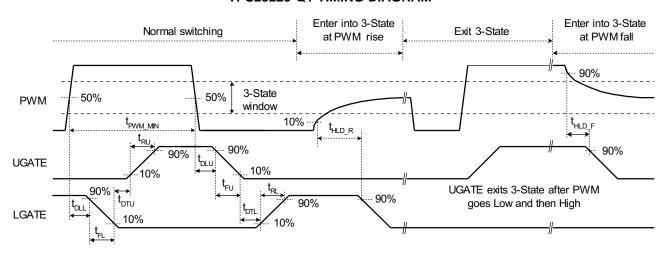
TRUTH TABLE

		V_{DD} FALLING > 3 V AND $T_{\rm J}$ < 150°C							
PIN	V_{DD} RISING < 3.5 V	EN/DO DICINO		EN/PG FALLING > 1.0 V					
	OR T _J > 160°C	EN/PG RISING < 1.7 V	PWM < 1 V	PWM > 1.5 V AND T _{RISE} /T _{FALL} < 200 ns	PWM SIGNAL SOURCE IMPEDANCE >40 kΩ FOR > 250ns (3-State) ⁽¹⁾				
LGATE	Low	Low	High	Low	Low				
UGATE	Low	Low	Low	High	Low				
EN/PG	Low								

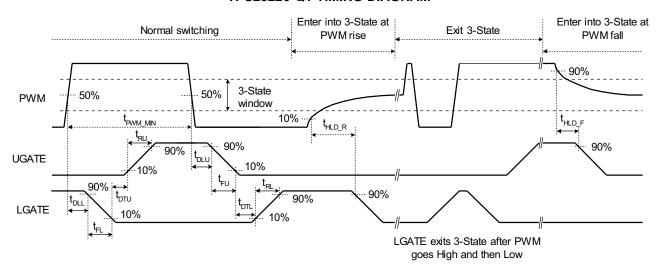
⁽¹⁾ To exit the 3-state condition, the PWM signal should go low. One Low PWM input signal followed by one High PWM input signal is required before re-entering the 3-state condition.



TPS28225-Q1 TIMING DIAGRAM



TPS28226-Q1 TIMING DIAGRAM



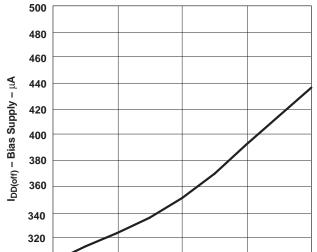
300

-40



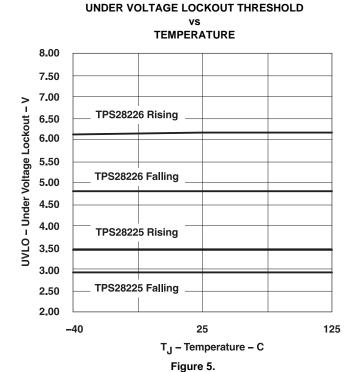
TYPICAL CHARACTERISTICS

BIAS SUPPLY CURRENT vs TEMPERATURE (V_{EN/PG} = Low, PWM Input Floating, V_{DD} = 7.2V)

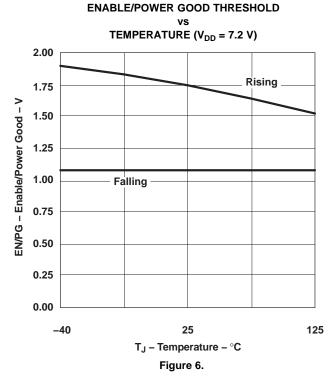


 T_J – Temperature – °C Figure 4.

25



125



PWM 3-STATE THRESHOLDS, (5-V Input Pulses)
vs

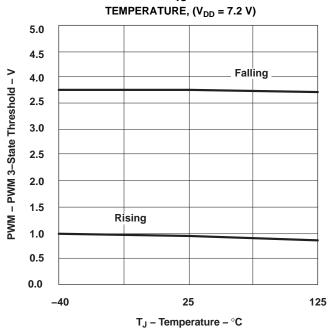
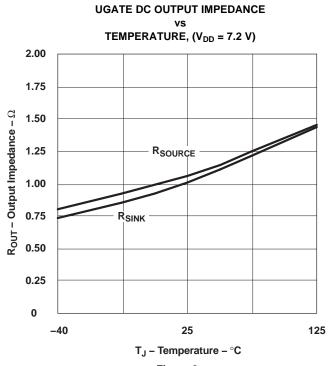


Figure 7.

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TYPICAL CHARACTERISTICS (continued)



TEMPERATURE (V_{DD} = 7.2 V) 2.00 1.75 1.50 1.25 0.50 R_{SOURCE} 0.25

25

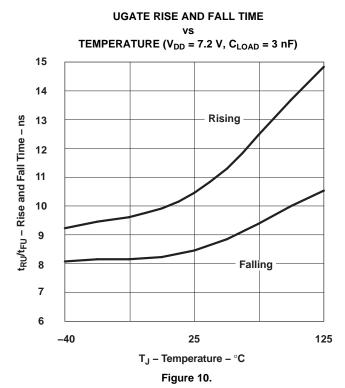
T_J - Temperature - °C

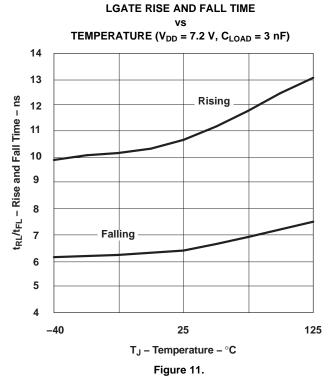
Figure 9.

LGATE DC OUTPUT IMPEDANCE

Figure 8.

-40

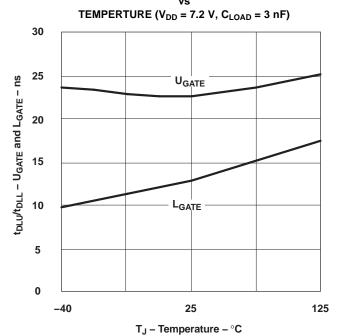




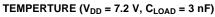


TYPICAL CHARACTERISTICS (continued)

UGATE AND LGATE (Turning OFF Propagation Delays)



UGATE AND LGATE (Dead Time)



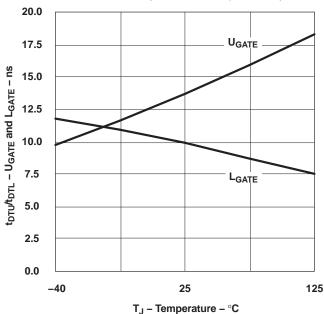
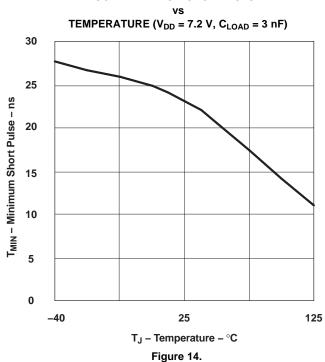
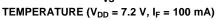


Figure 12. Figure 13.

UGATE MINIMUM SHORT PULSE



BOOTSTRAP DIODE FORWARD VOLTAGE



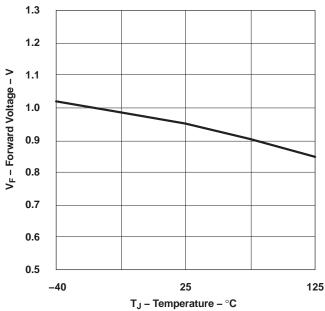


Figure 15.



TYPICAL CHARACTERISTICS (continued)

BIAS SUPPLY CURRENT vs SWITCHING FREQUENCY (V_{DD} = 7.2 V, No Load, T_J = 25°C) 15 4 10 100 300 500 700 900 1100 1300 1500 1700 1900 F_{SW} – Switching Frequency – kHz

DRIVER DISSIPATED POWER vs SWITCHING FREQUENCY (Different Load Charge, V_{DD} = 7.2 V, T_{J} = 25°C)

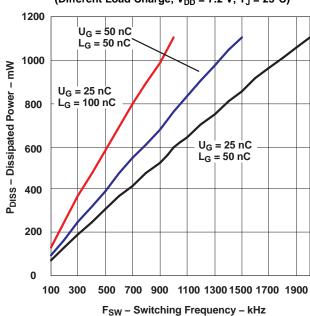


Figure 17.

PWM INPUT RISING SWITCHING WAVEFORMS

Figure 16.

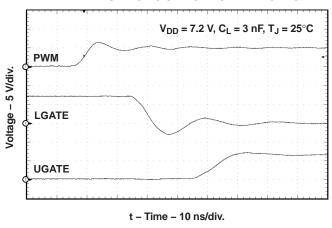
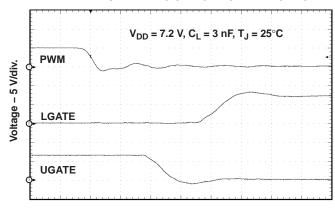


Figure 18.

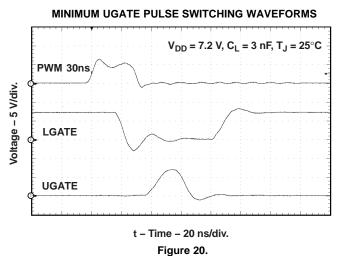
PWM INPUT FALLING SWITCHING WAVEFORMS



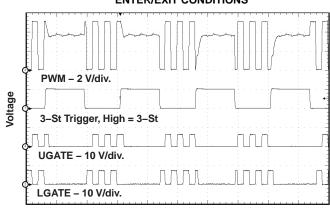
t - Time - 10 ns/div. Figure 19.



TYPICAL CHARACTERISTICS (continued)



NORMAL AND 3-STATE OPERATION ENTER/EXIT CONDITIONS



t – Time – 5 μ s/div. Figure 21.



DETAILED DESCRIPTION

Under Voltage Lockout (UVLO)

The TPS2822x-Q1 incorporates an under voltage lockout circuit that keeps the driver disabled and external power FETs in an OFF state when the input supply voltage V_{DD} is insufficient to drive external power FETs reliably. During power up, both gate drive outputs remain low until voltage V_{DD} reaches UVLO threshold, typically 3.5 V for the TPS2822x-Q1 and and 6.35 V for the TPS28226-Q1. Once the UVLO threshold is reached, the condition of gate drive outputs is defined by the input PWM and EN/PG signals. During power down the UVLO threshold is set lower, typically 3.0 V for the TPS2822x-Q1 and 5.0 V for the TPS28226-Q1. The 0.5-V for the TPS2822x-Q1 and 1.35 V for the TPS28226-Q1 hysteresis is selected to prevent the driver from turning ON and OFF while the input voltage crosses UVLO thresholds, especially with low slew rate. The TPS2822x-Q1 has the ability to send a signal back to the system controller that the input supply voltage V_{DD} is insufficient by internally pulling down the EN/PG pin. The TPS2822x-Q1 releases EN/PG pin immediately after the V_{DD} has risen above the UVLO threshold.

Output Active Low

The output active low circuit effectively keeps the gate outputs low even if the driver is not powered up. This prevents open gate conditions on the external power FETs and accidental turn ON when the main power stage supply voltage is applied before the driver is powered up. For the simplicity, the output active low circuit is shown in a block diagram as the resistor connected between LGATE and GND pins with another one connected between UGATE and PHASE pins.



Enable/Power Good

The Enable/Power Good circuit allows the TPS2822x-Q1 to follow the PWM input signal when the voltage at EN/PG pin is above 2.1 V maximum. This circuit has a unique two-way communication capability. This is illustrated by Figure 22.

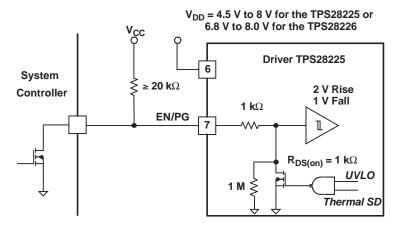


Figure 22. Enable/Power Good Circuit

The EN/PG pin has approximately 1-k Ω internal series resistor. Pulling EN/PG high by an external \geq 20-k Ω resistor allows two-way communication between controller and driver. If the input voltage V_{DD} is below UVLO threshold or thermal shut down occurs, the internal MOSFET pulls EN/PG pin to GND through 1-k Ω resistor. The voltage across the EN/PG pin is now defined by the resistor divider comprised by the external pull up resistor, 1-k Ω internal resistor and the internal FET having 1-k Ω R_{DS(on)}. Even if the system controller allows the driver to start by setting its own enable output transistor OFF, the driver keeps the voltage at EN/PG low. Low EN/PG signal indicates that the driver is not ready yet because the supply voltage V_{DD} is low or that the driver is in thermal shutdown mode. The system controller can arrange the delay of PWM input signals coming to the driver until the driver releases EN/PG pin. If the input voltage V_{DD} is back to normal, or the driver is cooled down below its lower thermal shutdown threshold, then the internal MOSFET releases the EN/PG pin and normal operation resumes under the external Enable signal applied to EN/PG input. Another feature includes an internal 1-M Ω resistor that pulls EN/PG pin low and disables the driver in case the system controller accidentally loses connection with the driver. This could happen if, for example, the system controller is located on a separate PCB daughter board.

The EN/PG pin can serve as the second pulse input of the driver additionally to PWM input. The delay between EN/PG and the UGATE going high, provided that PWM input is also high, is only about 30ns. If the PWM input pulses are synchronized with EN/PG input, then when PWM and EN/PG are high, the UGATE is high and LGATE is low. If both PWM and EN/PG are low, then UGATE and LGATE are both low as well. This means the driver allows operation of a synchronous buck regulator as a convertional buck regulator using the body diode of the low side power MOSFET as the freewheeling diode. This feature can be useful in some specific applications to allow startup with a pre-biased output or, to improve the efficiency of buck regulator when in power saving mode with low output current.



3-State Input

As soon as the EN/PG pin is set high and input PWM pulses are initiated (see Note below). The dead-time control circuit ensures that there is no overlapping between UGATE and LGATE drive outputs to eliminate shoot through current through the external power FETs. Additionally to operate under periodical pulse sequencing, the TPS2822x-Q1 has a self-adjustable PWM 3-state input circuit. The 3-state circuit sets both gate drive outputs low, and thus turns the external power FETs OFF if the input signal is in a high impedance state for at least 250 ns typical. At this condition, the PWM input voltage level is defined by the internal $27k\Omega$ to $13k\Omega$ resistor divider shown in the block diagram. This resistor divider forces the input voltage to move into the 3-state window. Initially the 3-state window is set between 1.0-V and 2.0-V thresholds. The lower threshold of the 3-state window is always fixed at about 1.0 V. The higher threshold is adjusted to about 75% of the input signal amplitude. The self-adjustable upper threshold allows shorter delay if the input signal enters the 3-state window while the input signal was high, thus keeping the high-side power FET in ON state just slightly longer than 250 ns time constant set by an internal 3-state timer. Both modes of operation, PWM input pulse sequencing and the 3-state condition, are illustrated in the timing diagrams shown in Figure 21. The self-adjustable upper threshold allows operation in wide range amplitude of input PWM pulse signals. The waveforms in Figure 23 and Figure 24 illustrates the TPS28225-Q1 operation at normal and 3-state mode with the input pulse amplitudes 6 V and 2.5 V accordingly. After entering into the 3-state window and staying within the window for the hold-off time, the PWM input signal level is defined by the internal resistor divider and, depending on the input pulse amplitude, can be pulled up above the normal PWM pulse amplitude (Figure 24) or down below the normal input PWM pulse (Figure 23).

TPS28225-Q1 3-State Exit Mode:

To exit the 3-state operation mode, the PWM signal should go low and then high at least once.

TPS28226-Q1 3-State Exit Mode:

To exit the 3-state operation mode, the PWM signal should go high and then low at least once.

This is necessary to restore the voltage across the bootstrap capacitor that could be discharged during the 3-state mode if the 3-state condition lasts long enough.

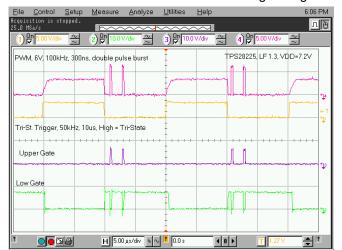




Figure 23. 6-V Amplitude PWM Pulse (TPS28225-Q1)

Figure 24. 2.5-V Amplitude PWM Pulse (TPS28225-Q1)

NOTE

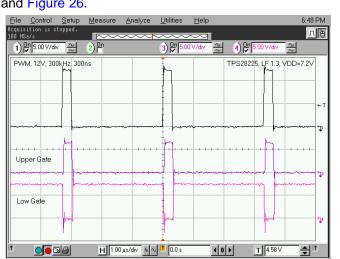
The driver sets UGATE low and LGATE high when PWM is low. When the PWM goes high, UGATE goes high and LGATE goes low.



IMPORTANT NOTE: Any external resistor between PWM input and GND with the value lower than $40k\Omega$ can interfere with the 3-state thresholds. If the driver is intended to operate in the 3-state mode, any resistor below $40k\Omega$ at the PWM and GND should be avoided. A resistor lower than $3.5k\Omega$ connected between the PWM and GND completely disables the 3-state function. In such case, the 3-state window shrinks to zero and the lower 3-state threshold becomes the boundary between the UGATE staying low and LGATE being high and vice versa depending on the PWM input signal applied. It is not necessary to use a resistor <3.5k Ω to avoid the 3-state condition while using a controller that is 3-state capable. If the rise and fall time of the input PWM signal is shorter than 250ns, then the driver never enter into the 3-state mode.

In the case where the low-side MOSFET of a buck converter stays on during shutdown, the 3-state feature can be fused to avoid negative resonent voltage across the output capacitor. This feature also can be used during start up with a pre-biased output in the case where pulling the output low during the startup is not allowed due to system requirements. If the system controller does not have the 3-state feature and never goes into the high-impedance state, then setting the EN/PG signal low will keep both gate drive outputs low and turn both low- and high-side MOSFETs OFF during the shut down and start up with the pre-biased output.

The self-adjustable input circuit accepts wide range of input pulse amplitudes (2V up to 13.2V) allowing use of a variety of controllers with different outputs including logic level. The wide PWM input voltage allows some flexibility if the driver is used in secondary side synchronous rectifier circuit. The operation of the TPS2822x-Q1 with a 12-V input PWM pulse amplitude, and with $V_{DD} = 7.2V$ and $V_{DD} = 5V$ respectively is shown in Figure 25 and Figure 26.





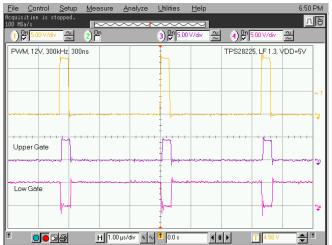


Figure 26. 12-V PWM Pulse at $V_{DD} = 5 \text{ V}$



Bootstrap Diode

The bootstrap diode provides the supply voltage for the UGATE driver by charging the bootstrap capacitor connected between BOOT and PHASE pins from the input voltage VDD when the low-side FET is in ON state. At the very initial stage when both power FETs are OFF, the bootstrap capacitor is pre-charged through this path including the PHASE pin, output inductor and large output capacitor down to GND. The forward voltage drop across the diode is only 1.0V at bias current 100 mA. This allows quick charge restore of the bootstrap capacitor during the high-frequency operation.

Upper And Lower Gate Drivers

The upper and lower gate drivers charge and discharge the input capacitance of the power MOSFETs to allow operation at switching frequencies up to 2 MHz. The output stage consists of a P-channel MOSFET providing source output current and an N-channel MOSFET providing sink current through the output stage. The ON state resistances of these MOSFETs are optimized for the synchronous buck converter configuration working with low duty cycle at the nominal steady state condition. The UGATE output driver is capable of propagating PWM input puses of less than 30-ns while still maintaining proper dead time to avoid any shoot through current conditions. The waveforms related to the narrow input PWM pulse operation are shown in Figure 20.

Dead-Time Control

The dead-time control circuit is critical for highest efficiency and no shoot through current operation througout the whole duty cycle range with the different power MOSFETs. By sensing the output of driver going low, this circuit does not allow the gate drive output of another driver to go high until the first driver output falls below the specified threshold. This approach to control the dead time is called adaptive. The overall dead time also includes the fixed portion to ensure that overlapping never exists. The typical dead time is around 14 ns, although it varies over the driver internal tolerances, layout and external MOSFET parasitic inductances. The proper dead time is maintained whenever the current through the output inductor of the power stage flows in the forward or reverse direction. Reverse current could happen in a buck configuration during the transients or while dynamically changing the output voltage on the fly, as some microprocessors require. Because the dead time does not depend on inductor current direction, this driver can be used both in buck and boost regulators or in any bridge configuration where the power MOSFETs are switching in a complementary manner. Keeping the dead time at short optimal level boosts efficiency by 1% to 2% depending on the switching frequency. Measured switching waveforms in one of the practical designs show 10-ns dead time for the rising edge of PHASE node and 22 ns for the falling edge (Figure 32 and Figure 33 in the Application Section of the data sheet).

Large non-optimal dead time can cause duty cycle modulation of the dc-to-dc converter during the operation point where the output inductor current changes its direction right before the turn ON of the high-side MOSFET. This modulation can interfere with the controller operation and it impacts the power stage frequency response transfer function. As the result, some output ripple increase can be observed. The TPS2822x-Q1 driver is designed with the short adaptive dead time having fixed delay portion that eliminates risk of the effective duty cycle modulation at the described boundary condition.

Thermal Shutdown

If the junction temperature exceeds 160°C, the thermal shutdown circuit will pull both gate driver outputs low and thus turning both, low-side and high-side power FETs OFF. When the driver cools down below 140°C after a thermal shutdown, then it resumes its normal operation and follows the PWM input and EN/PG signals from the external control circuit. While in thermal shutdown state, the internal MOSFET pulls the EN/PG pin low, thus setting a flag indicating the driver is not ready to continue normal operation. Normally the driver is located close to the MOSFETs, and this is usually the hottest spots on the PCB. Thus, the thermal shutdown feature of TPS2822x-Q1 can be used as an additional protection for the whole system from overheating.



APPLICATION INFORMATION

Switching The MOSFETs

Driving the MOSFETs efficiently at high switching frequencies requires special attention to layout and the reduction of parasitic inductances. Efforts need to be done both at the driver's die and package level and at the PCB layout level to keep the parasitic inductances as low as possible. Figure 27 shows the main parasitic inductances and current flow during turning ON and OFF of the MOSFET by charging its C_{GS} gate capacitance.

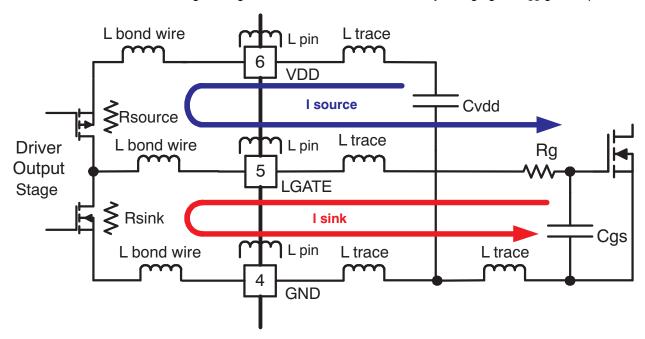
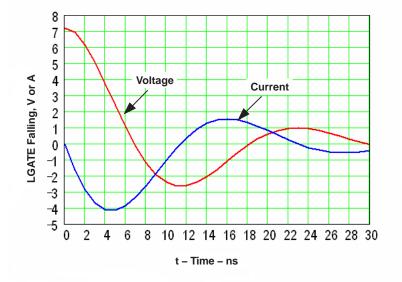


Figure 27. MOSFET Drive Paths and Main Circuit Parasitics



The I_{SOURCE} current charges the gate capacitor and the I_{SINK} current discharges it. The rise and fall time of voltage across the gate defines how quickly the MOSFET can be switched. The timing parameters specified in datasheet for both upper and lower driver are shown in Figure 18 and Figure 19 where 3-nF load capacitor has been used for the characterization data. Based on these actual measurements, the analytical curves in Figure 28 and Figure 29 show the output voltage and current of upper and low side drivers during the discharging of load capacitor. The left waveforms show the voltage and current as a function of time, while the right waveforms show the relation between the voltage and current during fast switching. These waveforms show the actual switching process and its limitations because of parasitic inductances. The static V_{OUT}/I_{OUT} curves shown in many datasheets and specifications for the MOSFET drivers do not replicate actual switching condition and provide limited information for the user.



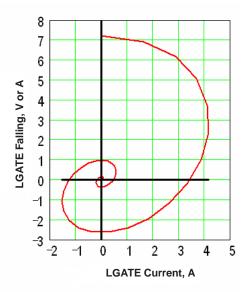
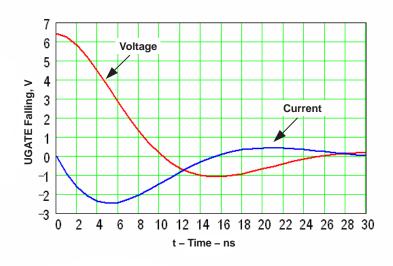


Figure 28. LGATE Turning Off Voltage and Sink Current vs Time (Related Switching Diagram (right))



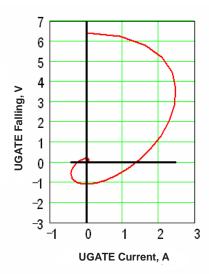


Figure 29. UGATE Turning Off Voltage and Sink Current vs Time (Related Switching Diagram (right))



Turning Off of the MOSFET needs to be done as fast as possible to reduce switching losses. For this reason the TPS2822x-Q1 driver has very low output impedance specified as 0.4Ω typ for lower driver and 1Ω typ for upper driver at dc current. Assuming 8-V drive voltage and no parasitic inductances, one can expect an initial sink current amplitude of 20A and 8A respectively for the lower and upper drivers. With pure R-C discharge circuit for the gate capacitor, the voltage and current waveforms are expected to be exponential. However, because of parasitic inductances, the actual waveforms have some ringing and the peak current for the lower driver is about 4A and about 2.5A for the upper driver (Figure 28 and Figure 29). The overall parasitic inductance for the lower drive path is estimated as 4nH and for the upper drive path as 6nH. The internal parasitic inductance of the driver, which includes inductances of bonded wires and package leads, can be estimated for SOIC-8 package as 2nH for lower gate and 4nH for the upper gate. Use of DFN-8 package reduces the internal parasitic inductances by approximately 50%.

Layout Recommendations

To improve the switching characteristicsand efficiency of a design, the following layout rules need to be followed.

- Locate the driver as close as possible to the MOSFETs.
- Locate the V_{DD} and bootstrap capacitors as close as possible to the driver.
- Pay special attention to the GND trace. Use the thermal pad of the DFN-8 package as the GND by
 connecting it to the GND pin. The GND trace or pad from the driver goes directly to the source of the
 MOSFET but should not include the high current path of the main current flowing through the drain and
 source of the MOSFET.
- Use a similar rule for the PHASE node as for the GND.
- Use wide traces for UGATE and LGATE closely following the related PHASE and GND traces. Eighty to 100
 mils width is preferable where possible.
- Use at least 2 or more vias if the MOSFET driving trace needs to be routed from one layer to another. For the GND the number of vias are determined not only by the parasitic inductance but also by the requirements for the thermal pad.
- Avoid PWM and enable traces going close to the PHASE node and pad where high dV/dT voltage can induce significant noise into the relatively high impedance leads.

It should be taken into account that poor layout can cause 3% to 5% less efficiency versus a good layout design and can even decrease the reliability of the whole system.

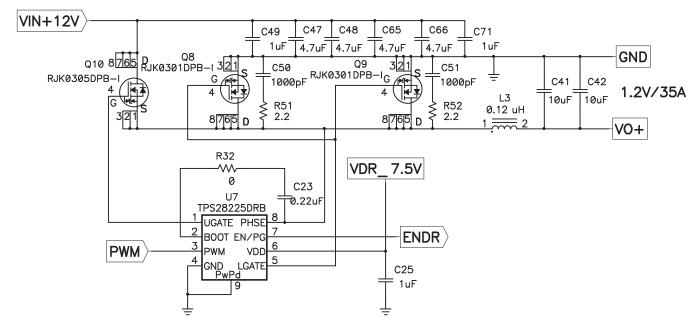


Figure 30. One of Four Phases Driven by TPS2822x-Q1 Driver in 4-phase VRM Reference Design



The schematic of one of the phases in a multi-phase synchronous buck regulator and the related layout are shown in Figure 30 and Figure 31. These help to illustrate good design practices. The power stage includes one high-side MOSFET Q10 and two low-side MOSFETS (Q8 and Q9). The driver (U7) is located on bottom side of PCB close to the power MOSFETs. The related switching waveforms during turning ON and OFF of upper FET are shown in Figure 32 and Figure 33. The dead time during turning ON is only 10ns (Figure 32) and 22ns during turning OFF (Figure 33).

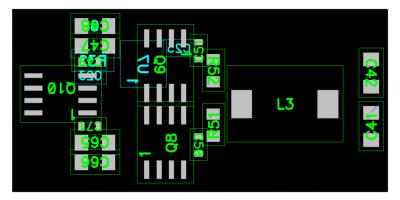


Figure 31. Component Placement Based on Schematic in Figure 30



Figure 32. Phase Rising Edge Switching Waveforms (20ns/div) of the Power Stage in Figure 30



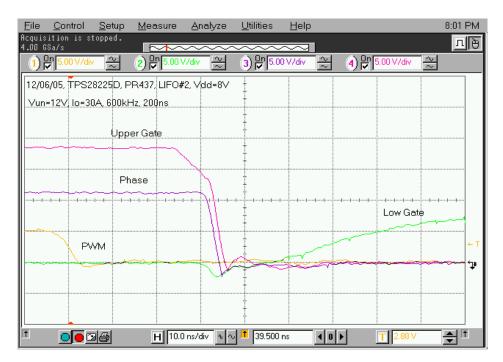


Figure 33. Phase Falling Edge Switching Waveforms (10ns/div) of the Power State in Figure 30

List of Materials

The list of materials for this specific example is provided in the table. The component vendors are not limited to those shown in the table below. It should be notd that, in this example, the power MOSFET packages were chosen with drains on top. The decoupling capacitors C47, C48, C65, and C66 were chosen to have low profiles. This allows the designer to meet good layout rules and place a heatsink on top of the FETs using an electrically isolated and thermally conductive pad.

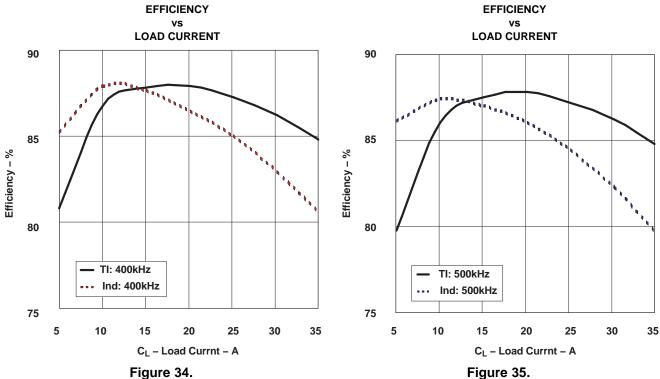
Table 1. List of Materials

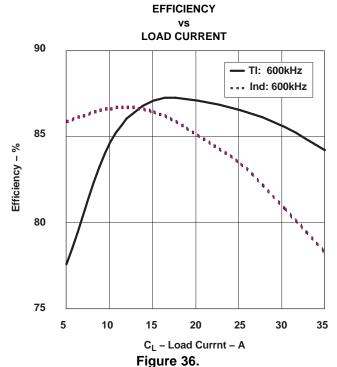
REF DES	COUNT	DESCRIPTION	MANUFACTURE	PART NUMBER
C47, C48, C65, C66	4	Capacitor, ceramic, 4.7 µF, 16 V, X5R 10%, low profile 0.95 mm, 1206	TDK	C3216X5R1C475K
C41, C42	2	Capacitor, ceramic, 10 µF, 16 V, X7R 10%, 1206	TDK	C3216X7R1C106K
C50, C51	2	Capacitor, ceramic, 1000 pF, 50 V, X7R, 10%, 0603	Std	Std
C23	1	Capacitor, ceramic, 0.22 µF, 16 V, X7R, 10%, 0603	Std	Std
C25, C49, C71	3	Capacitor, ceramic, 1 µF, 16 V, X7R, 10%, '0603	Std	Std
L3	1	Inductor, SMT, 0.12 μH, 31 A, 0.36 mΩ, 0.400 x 0.276	Pulse	PA0511-101
Q8, Q9	2	Mosfet, N-channel, V_{DS} 30 V, R_{DS} 2.4 m Ω , I_{D} 45 A, LFPAK-i	Renesas	RJK0301DPB-I
Q10	1	Mosfet, N-channel, V _{DS} 30 V, R _{DS} 6.2 mΩ, I _D 30 A, LFPAK-i	Renesas	RJK0305DPB-I
R32	1	Resistor, chip, 0 Ω, 1/10 W, 1%, '0805	Std	Std
R51, R52	2	Resistor, chip, 2.2 Ω, 1/10 W, 1%, '0805	Std	Std
U7	1	Device, High Frequency 4-A Sink Synchronous Buck MOSFET Driver, DFN-8	Texas Instruments	TPS28225-Q1DRB



Efficiency of Power Stage vs Load Current at Different Switching Frequencies

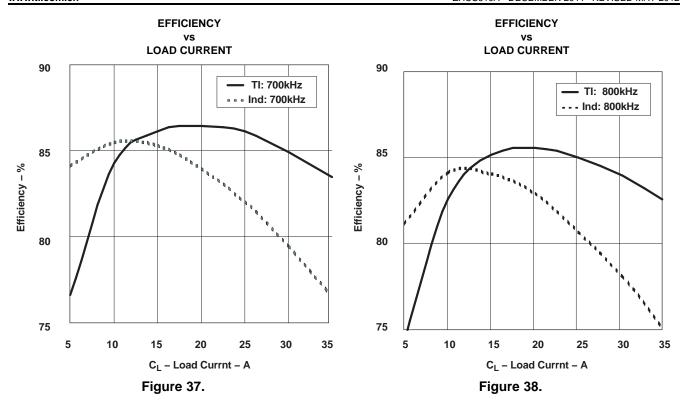
Efficiency achieved using TPS2822x-Q1 driver with 8-V drive at different switching frequencies a similar industry 5-V driver using the power stage in Figure 30 is shown in Figure 36, Figure 38, Figure 37, Figure 34 and Figure 35.



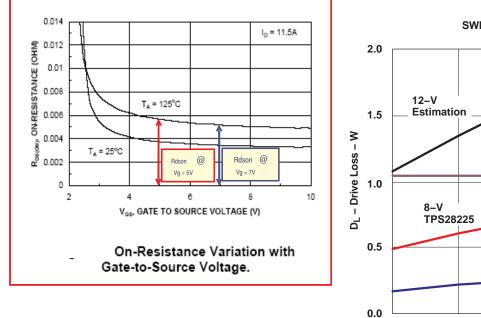


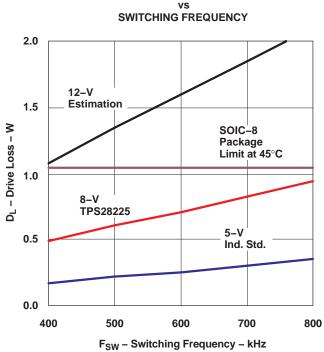
26





When using the same power stage, the driver with the optimal drive voltage and optimal dead time can boost efficiency up to 5%. The optimal 8-V drive voltage versus 5-V drive contributes 2% to 3% efficiency increase and the remaining 1% to 2% can be attributed to the reduced dead time. The 7-V to 8-V drive voltage is optimal for operation at switching frequency range above 400kHz and can be illustrated by observing typical $R_{DS(on)}$ curves of modern FETs as a function of their gate drive voltage. This is shown in Figure 39.





DRIVE LOSS

Figure 39. R_{DS(on)} of MOSFET as Function of V_{GS}

Figure 40. Drive Power as Function of V_{GS} and F_{SW}



The plots show that the $R_{DS(on)}$ at 5-V drive is substantially larger than at 7 V and above that the $R_{DS(on)}$ curve is almost flat. This means that moving from 5-V drive to an 8-V drive boosts the efficiency because of lower $R_{DS(on)}$ of the MOSFETs at 8 V. Further increase of drive voltage from 8 V to 12 V only slightly decreases the conduction losses but the power dissipated inside the driver increases dramatically (by 125%). The power dissipated by the driver with 5V, 8V and 12V drive as a function of switching frequency from 400 kHz to 800 kHz. It should be noted that the 12-V driver exceeds the maximum dissipated power allowed for an SOIC-8 package even at 400-kHz switching frequency.

RELATED PRODUCTS

- TPS40090, 2/3/4-Phase Multi-Phase Controller
- TPS40091, 2/3/4-Phase Multi-Phase Controller



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REVISION HISTORY

Cł	Changes from Original (December, 2011) to Revision A Page							
•	将 AEC-Q100 信息添加到了特性中。	1						
•	Added AEC-Q100 info to ESD rating in Abs Max table and changed the CDM from 500 to 750 V	5						



PACKAGE OPTION ADDENDUM

10-Dec-2020

PACKAGING INFORMATION

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Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TPS28225TDRBRQ1	ACTIVE	SON	DRB	8	3000	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 105	PXND	Samples
TPS28225TDRQ1	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 105	28225T	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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10-Dec-2020

PACKAGE MATERIALS INFORMATION

www.ti.com 14-Mar-2013

TAPE AND REEL INFORMATION





Α0	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing			Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPS28225TDRBRQ1	SON	DRB	8	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2

PACKAGE MATERIALS INFORMATION

www.ti.com 14-Mar-2013



*All dimensions are nominal

Device Package Type		Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
TPS28225TDRBRQ1	SON	DRB	8	3000	367.0	367.0	35.0	



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4203482/L





PLASTIC SMALL OUTLINE - NO LEAD



NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC SMALL OUTLINE - NO LEAD



NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC SMALL OUTLINE - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.





SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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